

# VLSI System Design

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## Detailed Topics:

### **1. Introduction to Digital Integrated Circuits**

- 1.1. A Historical Perspective
- 1.2. Design Issues in Digital Integrated Circuits
- 1.3. Quality Metrics of a Digital Design

### **2. CMOS Technology Processing and Layout**

- 2.1. Manufacturing CMOS Integrated Circuits
- 2.2. Design Rules
- 2.3. Packaging Integrated Circuits

### **3. MOS Modeling**

- 3.1. The Threshold Voltage, Operation in Different Regions and I/V Characteristics
- 3.2. Second-Order Effects: Body Effect, Channel Length Modulation
- 3.3. Short-Channel Effects: Mobility Degradation, Velocity Saturation
- 3.4. Parasitic Capacitances
- 3.5. Models for Hand Analysis
- 3.6. CMOS Latch-Up
- 3.7. SPICE Models
- 3.8. Technology Scaling

### **4. Interconnects in CMOS Technology**

- 4.1. Interconnect Parameters: Capacitance, Resistance, Inductance
- 4.2. Electrical Wire Models: Lumped C Model, Lumped RC Model, Distributed RC Model
- 4.3. Advanced Interconnect Techniques: Reduced Swing, Current Mode
- 4.4. SPICE Wire Models

### **5. The CMOS Inverter**

- 5.1. The Static Behavior: Switching Threshold, Noise Margins, Robustness
- 5.2. The Dynamic Behavior: Propagation Delay, Device Sizing for a Chain of Inverters, Optimal Buffer Design
- 5.3. Power Dissipation: Dynamic, Switching Activity, Short-Circuit, Static or Leakage, Energy-Delay Product, Analyzing Power Consumption Using SPICE
- 5.4. Impact of Technology Scaling

### **6. Combinational CMOS Logic Gates**

- 6.1. Combinational vs. Sequential Logic
- 6.2. Static CMOS Logic Design: Complementary CMOS, Ratioed Logic, Pass Transistor Logic
- 6.3. Dynamic CMOS Logic: Basic Principles, Speed and Power Dissipation, Issues in Dynamic Logic Design, Cascading Dynamic Gates, Domino Logic

## **7. Sequential Logic Circuits**

- 7.1. Static Latches and Registers
- 7.2. Dynamic Latches and Registers

## **8. Timing Issues in Digital Circuits**

- 8.1. Timing Classification of Digital Systems
- 8.2. Synchronous Interconnect and Design
- 8.3. Clock Distribution Techniques
- 8.4. Self-Time or Asynchronous Circuit Design

## **9. Verilog RTL Modeling of Digital Systems**

## **10. Arithmetic and Logic Building Blocks**

- 10.1. The Adders: Binary Adder, Full Adder
- 10.2. The Multiplier
- 10.3. The Shifter: Barrel Shifter, Logarithmic Shifter

## **11. Memory Design in CMOS**

- 11.1. Classification, Architectures and Building Blocks
- 11.2. The Memory Core: Read-Only Memories (ROMs), Nonvolatile Read-Write Memories, Read-Write Memories (RAM)
- 11.3. Peripheral Circuitry: Address Decoders, Sense Amplifiers, Voltage References, Drivers & Buffers, Timing and Control
- 11.4. SRAM Design

## **12. Testing of Digital Systems**

- 12.1. Introduction, Test Procedure
- 12.2. Design for Testability
- 12.3. Test Pattern Generation

## **References:**

1. J. M. Rabaey, A. Chandrakasan, and B. Nicolic, *Digital Integrated Circuits: A Design Perspective*, New Jersey: Prentice Hall, 2003 (**Primary Text**).
2. K. W. Martin, *Digital Integrated Circuit Design*, New York: Oxford University Press, 2000.
3. N. H. E. Weste and David Harris, *CMOS VLSI Design: A Circuit and Systems Perspective*. Third Edition, Boston: Addison-Wesley, 2005.
4. Z. Navabi, *Verilog Digital System Design*, New York: McGraw-Hill, 1999.
5. Class Notes and Selected Publications.

## **Requirement:**

Electronics II

## **Grading:**

Homeworks and Design Projects: 30%  
Midterm Exam: 30%  
Final Exam: 40%